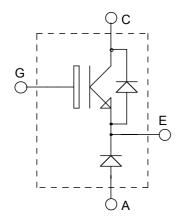


ISOTOP® Buck chopper NPT IGBT

$$V_{CES} = 600V$$

 $I_{C} = 60A @ Tc = 95°C$



Application

- AC and DC motor control
- Switched Mode Power Supplies

Features

- Non Punch Through (NPT) THUNDERBOLT IGBT
 - Low voltage drop
 - Low tail current
 - Switching frequency up to 100 kHz
 - Soft recovery parallel diodes
 - Low diode VF
 - Low leakage current
 - RBSOA and SCSOA rated
- ISOTOP® Package (SOT-227)
- Very low stray inductance
- High level of integration



- Outstanding performance at high frequency operation
- Stable temperature behavior
- Very rugged
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Easy paralleling due to positive T_C of V_{CEsat}
- **RoHS Compliant**



Absolute maximum ratings

Symbol	Parameter			Max ratings	Unit
V_{CES}	Collector - Emitter Breakdown Voltage			600	V
I_{C1}			$T_C = 25^{\circ}C$	93	
I_{C2}			$T_C = 95^{\circ}C$	60	Α
I_{CM}	Pulsed Collector Current	$T_C = 25^{\circ}C$	360		
V_{GE}	Gate – Emitter Voltage	±20	V		
P_{D}	Maximum Power Dissipation		$T_C = 25$ °C	378	W
I_{LM}	RBSOA clamped Inductive load Current R_G =11 Ω		$T_C = 25^{\circ}C$	360	A
IF_{AV}	Maximum Average Forward Current	Duty cycle=0.5	$T_C = 80$ °C	30	A
IF_{RMS}	RMS Forward Current (Square wave, 50% duty)			39	Α

😭 🛦 🕬 📆 These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.



All ratings @ $T_j = 25^{\circ}C$ unless otherwise specified

Electrical Characteristics

	Symbol	Characteristic	Test Conditions		Min	Тур	Max	Unit
	BV_{CES}	Collector - Emitter Breakdown Voltage	$V_{GE} = 0V, I_C = 0.5 \text{mA}$		600			V
	I_{CES}	Zero Gate Voltage Collector Current	V GE U V	$T_j = 25$ °C			80	4
				$T_j = 125$ °C			2000	μΑ
	V _{CE(on)}	Collector Emitter on Voltage	$V_{GE} = 15V$	$T_j = 25$ °C		2.0	2.5	V
		Conector Emitter on Voltage	$I_C = 60A$	$T_j = 125$ °C			2.8	v
	$V_{GE(th)}$	Gate Threshold Voltage	$V_{GE} = V_{CE}, I_{C} = 500 \mu A$		3	4	5	V
	I_{GES}	Gate – Emitter Leakage Current	$V_{GE} = \pm 20V$, $V_{CE} = 0V$				±100	nA

Dynamic Characteristics

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
Cies	Input Capacitance	$V_{GE} = 0V$		3125	3590	pF
C_{oes}	Output Capacitance	$V_{CE} = 25V$		310	450	
C_{res}	Reverse Transfer Capacitance	f = 1MHz		180	310	
Q_{g}	Total gate Charge	$V_{GS} = 15V$		257	410	
Q_{ge}	Gate – Emitter Charge	$V_{\rm Bus} = 300 V$		19	30	nC
Q_{gc}	Gate - Collector Charge	$I_C = 60A$		120	180	
$T_{d(on)}$	Turn-on Delay Time	Resistive Switching (25°C)		20	40	
$T_{\rm r}$	Rise Time	$V_{GE} = 15V$ $V_{Bus} = 300V$		95	190	ns
$T_{d(off)}$	Turn-off Delay Time	$I_{\text{C}} = 60\text{A}$		315	470	
$T_{\rm f}$	Fall Time	$R_G = 5\Omega$		245	490	
$T_{d(on)}$	Turn-on Delay Time	Inductive Switching (25°C)		26	50	ns
T_{r}	Rise Time	$V_{GE} = 15V$		63	125	
$T_{d(off)}$	Turn-off Delay Time	$V_{\text{Bus}} = 400V$ $I_{\text{C}} = 60A$		395	590	
T_{f}	Fall Time	$R_G = 5\Omega$		68	140	
E_{ts}	Total switching Losses	G		3.4	7	mJ
$T_{d(on)}$	Turn-on Delay Time	Inductive Switching (150°C) $V_{GE} = 15V$ $V_{Bus} = 400V$ $I_{C} = 60A$ $R_{G} = 5\Omega$		25	50	ns
T_{r}	Rise Time			59	120	
$T_{d(off)}$	Turn-off Delay Time			430	650	
$T_{\rm f}$	Fall Time			65	130	
Eon	Turn-on Switching Energy			1.6	3.2	
E_{off}	Turn-off Switching Energy			2.4	4.8	mJ
E_{ts}	Total switching Losses			4.0	8.0	



Chopper ciode ratings and characteristics

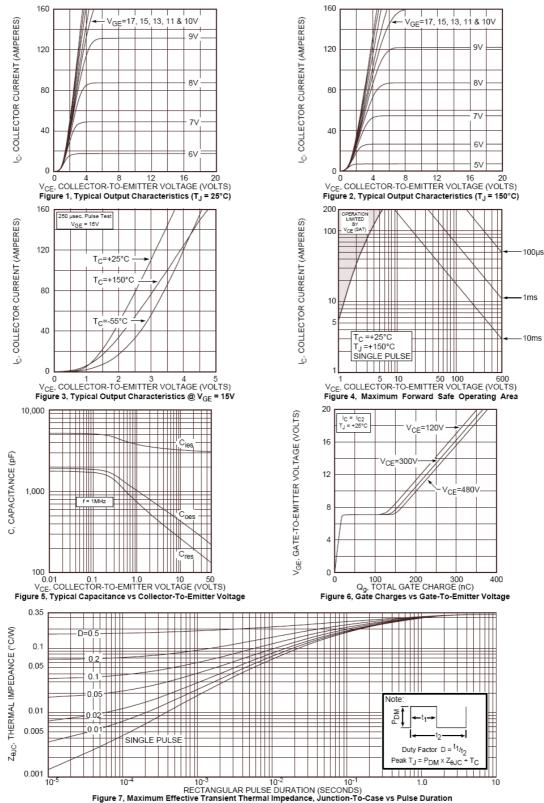
Symbol	Characteristic	Test Conditions		Min	Тур	Max	Unit
V_{F}	Diode Forward Voltage	$I_F = 30A$			1.6	1.8	
		$I_F = 60A$			1.9		V
		$I_F = 30A$	$T_{i} = 125^{\circ}C$		1.4		
I_{RM}	Maximum Reverse Leakage Current	$V_{R} = 600V$	$T_j = 25^{\circ}C$			250	
IRM		$V_{R} = 600V$	$T_j = 125$ °C			500	μΑ
C_{T}	Junction Capacitance	$V_{R} = 200V$			44		pF
4	Reverse Recovery Time	$I_F=1A, V_R=30V$ di/dt =100A/\(\mu\)s	$T_j = 25$ °C		23		ns
t_{rr}	Reverse Recovery Time	$I_F = 30A$ $T_i = 25^{\circ}C$	$T_i = 25^{\circ}C$		85		
			$T_{i} = 125^{\circ}C$		160		
T	Maximum Reverse Recovery Current		$T_i = 25^{\circ}C$		4		۸
I_{RRM}	Widaminin Reverse Recovery Current	$V_R = 400V$	$T_i = 125$ °C		8		A
0	Reverse Recovery Charge	$di/dt = 200A/\mu s$	$T_j = 25$ °C		130		, C
Q_{rr}			$T_{j} = 125^{\circ}C$		700		nC
t _{rr}	Reverse Recovery Time	$I_F = 30A$ $V_R = 400V$ $di/dt = 1000A/\mu s$			70		ns
Q_{rr}	Reverse Recovery Charge		$T_j = 125$ °C		1300		nC
I_{RRM}	Maximum Reverse Recovery Current				30		A

Thermal and package characteristics

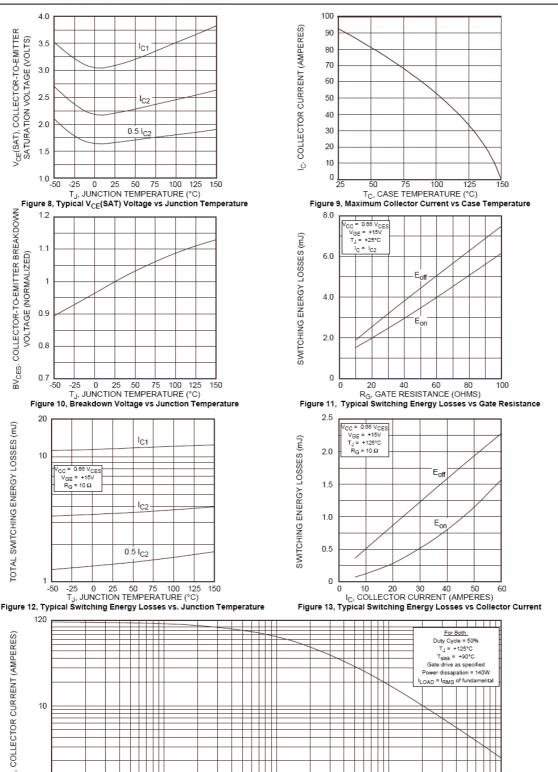
Symbol	Characteristic		Min	Тур	Max	Unit	
R_{thJC}	Junction to Case	IGBT			0.33	°C/W	
		Diode			1.21		
R_{thJA}	Junction to Ambient (IGBT & Diode)				20		
V_{ISOL}	RMS Isolation Voltage, any terminal to case t =1 min, 50/60Hz		2500			V	
T_{J}, T_{STG}	Storage Temperature Range		-55		150	°C	
$T_{ m L}$	Max Lead Temp for Soldering:0.063" from case for 10 sec				300		
Torque	Mounting torque (Mounting = 8-32 or 4mm Machine and terminals = 4mm Machine)				1.5	N.m	
Wt	Package Weight			29.2		g	



Typical IGBT Performance Curve







1000

10 F, FREQUENCY (KHz)

Figure 14, Typical Load Current vs Frequency

100

1.0

0.1



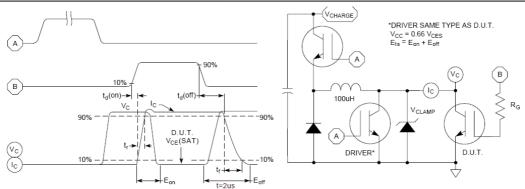


Figure 15, Switching Loss Test Circuit and Waveforms

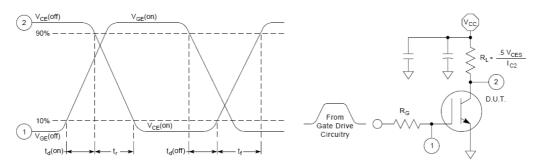
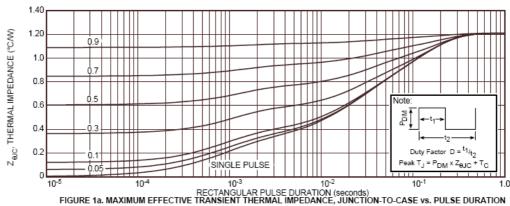


Figure 16, Resistive Switching Time Test Circuit and Waveforms

Typical Diode Performance Curve



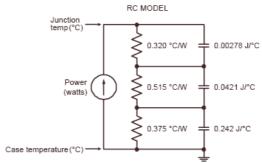


FIGURE 1b, TRANSIENT THERMAL IMPEDANCE MODEL



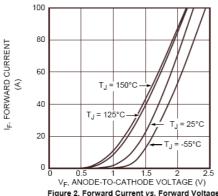


Figure 2. Forward Current vs. Forward Voltage

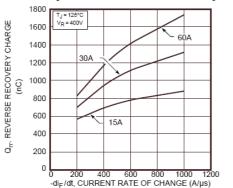


Figure 4. Reverse Recovery Charge vs. Current Rate of Change

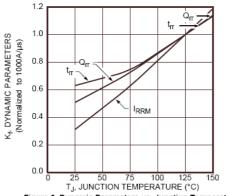


Figure 6. Dynamic Parameters vs. Junction Temperature

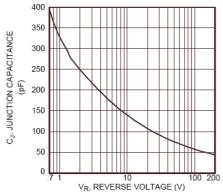


Figure 8. Junction Capacitance vs. Reverse Voltage

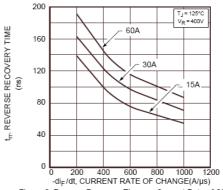


Figure 3. Reverse Recovery Time vs. Current Rate of Change

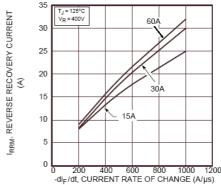


Figure 5. Reverse Recovery Current vs. Current Rate of Change

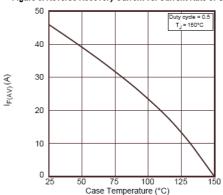


Figure 7. Maximum Average Forward Current vs. CaseTemperature



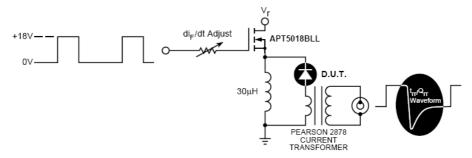
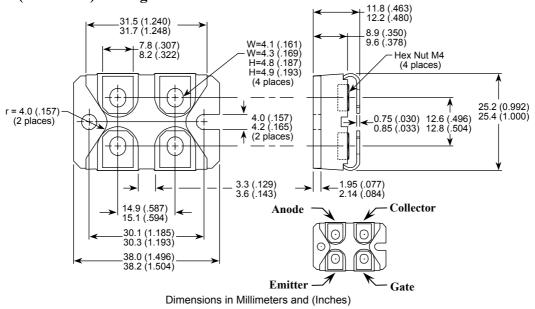


Figure 9. Diode Test Circuit

- 1 I_F Forward Conduction Current
 2 di_F/dt Rate of Diode Current Change Through Zero Crossing.
 3 I_{RRM} Maximum Reverse Recovery Current.
 4 t_{rr} Reverse Recovery Time, measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through I_{RRM} and 0.25 I_{RRM} passes through zero.
 5 Q_{rr} Area Under the Curve Defined by I_{RRM} and t_{rr}.
 - Figure 10, Diode Reverse Recovery Waveform and Definitions

SOT-227 (ISOTOP®) Package Outline



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